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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10082286	02/26/2002	250	3.	2878	

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****CONTINUING DATA VERIFIED:**

**** FOREIGN APPLICATIONS VERIFIED:**
JAPAN 2001-132668 04/27/2001

PG-PUB ☐ DO NOT PUBLISH ☐ RESCIND ☐

Foreign priority claimed ☐ yes ☐ no
35 USC 119 conditions met ☐ yes ☐ no
Verified and Acknowledged Examiners's initials

ATTORNEY DOCKET NO
H6808.0004/P004

TITLE : Semiconductor inspection system

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L(Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED		
		Total Claims		Print Claim for O.G.
Assistant Examiner				
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs.Drwg.	Print Fig.
		Application Examiner		
<input type="checkbox"/> TERMINAL DISCLAIMER		PREPARED FOR ISSUE		
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